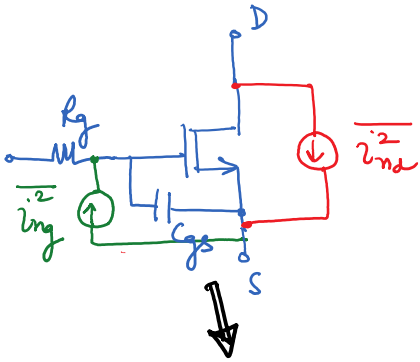


ECE 513 - Lecture 15

Tuesday, October 9, 2018 9:35 AM

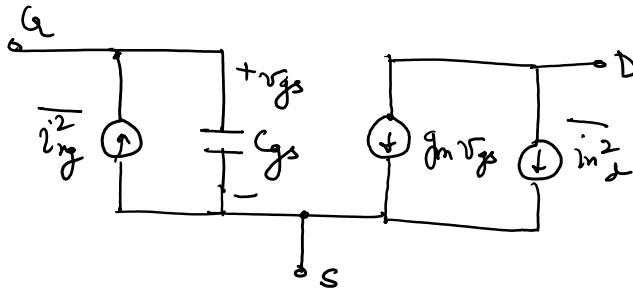
(T.H. Lee's Book)

Two-port Noise of MOSFET



$\overline{i_{ng}^2}$ is not due to R_g

↳ Thermal noise of the fluctuating channel which couples into the gate terminal, leading to noisy gate current.



Excess noise factor
 $= \frac{2}{3}$ for long-channel

$\overline{i_{nd}^2} = 4kT \gamma g_{ds} \Delta f$

$\gamma = 1 + \frac{k}{f}$
 flicker noise

g_{ds} at $V_{ds} = 0$
 $\approx k \mu_n \frac{W}{L} (V_{gs} - V_{th})$
 for long-channel CMOSFET

$$\overline{i_{ng}^2} = 4kT \gamma g_g \Delta f$$

"Van der Ziel model"

$$g_g = \frac{\omega^2 C_{gs}^2}{5 g_{ds0}} \leftarrow \text{noise coupled through } C_{gs}$$

Correlation coefficient:

$$C \equiv \frac{\overline{i_{ng} \cdot i_{nd}^*}}{\sqrt{\overline{i_{ng}^2} \cdot \overline{i_{nd}^2}}}$$

for long channel $C = -j0.395 \approx -j0.4$

* in short channel CMOS its within 2x range of the long-channel value

Assume:

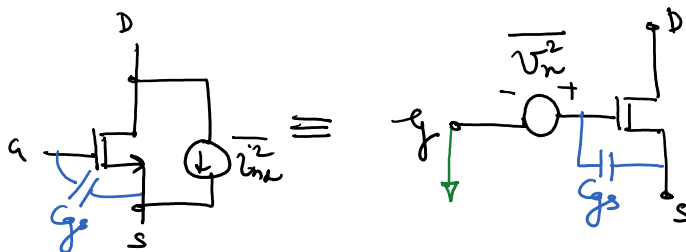
- * C remains at its long-channel value
- * Neglect thermal noise due to the resistive gate material (R_g)
- * Neglect C_{gs} to simplify derivation

* Need to find the two-port IEEE parameters

Tuesday, October 9, 2018 9:58 AM

$G_{s,opt}$, $B_{s,opt}$, f_{min} , G_u , R_n

Reflect the drain noise current to the gate (input) side



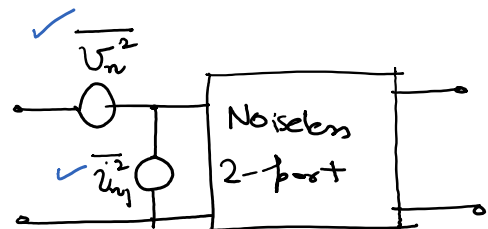
$$V_n = \frac{i_{na}}{g_m} \quad \leftarrow i_{na} = g_m V_{gs}$$

$$\Rightarrow \overline{V_n^2} = \frac{\overline{i_{na}^2}}{g_m^2}$$

$$\overline{V_n^2} = \frac{4kT\gamma g_{ds} \Delta f}{g_m^2}$$

we see here that this input noise voltage, V_n , is correlated with the drain noise current (and also in the same phase).

$$R_n \triangleq \frac{\overline{V_n^2}}{4kT\Delta f} = \frac{\gamma g_{ds}}{g_m^2}$$



* Also need to find $\overline{i_{n1}^2}$ due to the drain noise

To find $V_n \Rightarrow$ we short circuit the input port

To find $i_n \Rightarrow$ we open circuit the input port

$$\overline{i_{n1}^2} = \frac{\overline{i_{na}^2} (j\omega C_{gs})^2}{g_m^2} = \frac{4kT\gamma g_{ds} \Delta f (j\omega C_{gs})^2}{g_m^2} = \overline{V_n^2} \cdot (j\omega C_{gs})^2$$

* i_{n1} is correlated with V_n

Total input noise current = sum of reflected drain noise current + gate current noise

$$\Rightarrow \overset{\text{gate}}{\text{induced noise current}} (i_{ng}) = i_{ngc} + i_{ngu}$$

↑ correlated with i_{n1}
↑ uncorrelated with i_{n1}

$$\therefore i_n = i_u + Y_{cor} v_n$$

$$\Rightarrow Y_{cor} = \frac{i_{n1} + i_{ngc}}{v_n} = j\omega C_{gs} + \frac{i_{ngc}}{v_n}$$

$$= j\omega C_{gs} + \frac{g_m}{i_{nd}} \cdot i_{ngc} = \underbrace{j\omega C_{gs}} + \underbrace{g_m \cdot \left(\frac{i_{ngc}}{i_{nd}} \right)} \rightarrow \textcircled{1}$$

Need to express this explicitly in the form of correlation coefficient, ρ

* Need to perform algebraic manipulations to incorporate the correlation coefficient c .

We have

$$g_m \frac{v_{in_e}}{v_{in_d}} = g_m \frac{\overline{v_{in_e} \cdot v_{in_d}^*}}{\overline{v_{in_d} \cdot v_{in_d}^*}}$$

$$= g_m \frac{\overline{v_{in_e} \cdot v_{in_d}^*}}{\overline{v_{in_d}^2}}$$

$$= g_m \frac{\overline{v_{in_e} \cdot v_{in_d}^*}}{\overline{v_{in_d}^2}}$$

only v_{in_e} is correlated with v_{in_d}

going back to $\Sigma^n \textcircled{1}$

$$Y_{cor} = j\omega C_g + g_m \frac{\overline{v_{in_e} \cdot v_{in_d}^*}}{\overline{v_{in_d}^2}}$$

$$\Rightarrow \boxed{Y_{cor} = j\omega C_g + g_m \cdot c \sqrt{\frac{\overline{v_{in_e}^2}}{\overline{v_{in_d}^2}}}}$$

This explains all the algebraic manipulations

$$Y_{cr} = j\omega C_{gs} + g_m \cdot c \cdot \sqrt{\frac{g_m^2 C_{gs}^2}{58 g_{ds}}} = j\omega C_{gs} + \frac{g_m}{g_{ds}} \cdot c \cdot \sqrt{\frac{g_m}{58}} \cdot \omega C_{gs}$$

✓ from the equation for α_{ng}

Since $c = -j0.4$ for long-channel,

we assume $c = -j|c| \leftarrow c$ is purely imaginary

$$Y_{cr} = j\omega C_{gs} - j\omega C_{gs} \frac{g_m}{g_{ds}} |c| \sqrt{\frac{g_m}{58}} = \boxed{j\omega C_{gs} \left(1 - \alpha |c| \sqrt{\frac{g_m}{58}}\right)}$$

where $\alpha \triangleq \frac{g_m}{g_{ds}} \leq 1$ for long-channel MOSFETs
but shrinks with CMOS scaling

$$Y_{ur} = 0 + j\omega C_{gs} (1 - \alpha |c| \sqrt{\frac{\delta}{5\gamma}}) = g_{ur} + jB_{ur}$$

Y_{ur} is a scaled version of $j\omega C_{gs}$

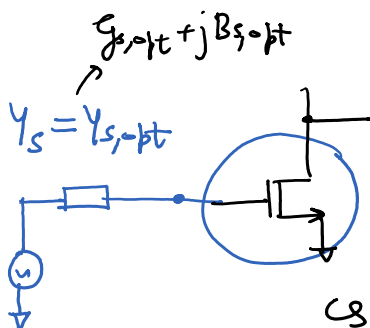
$$g_{ur} = 0$$

$$B_{ur} = \omega C_{gs} (1 - \alpha |c| \sqrt{\frac{\delta}{5\gamma}})$$

$$R_n \triangleq \frac{\overline{V_n^2}}{4kT \Delta f} = \frac{\gamma g_{do}}{g_m^2} = \frac{\gamma}{2} \cdot \frac{1}{g_m}$$

$$g_u = ?$$

$$g_u \triangleq \frac{\overline{i_u^2}}{4kT \Delta f} = \frac{4kT \Delta f \delta g_g (1 - |c|^2)}{4kT \Delta f} = \boxed{\frac{\delta \omega^2 C_{gs} (1 - |c|^2)}{5 g_{do}}}$$



for $F = F_{min}$

$$B_{s,opt} = -B_{ur} = -\omega C_{gs} (1 - \alpha |c| \sqrt{\frac{\delta}{5\gamma}})$$

$$g_{s,opt} = \sqrt{\frac{g_u}{R_n} + g_{ur}} = \alpha \omega C_{gs} \sqrt{\frac{\delta}{5\gamma}} (1 - |c|^2)$$

$$F = F_{min} = 1 + 2R_n (g_{s,opt} + g_{ur})$$

$$\leq 1 + \frac{2}{\sqrt{5}} \cdot \frac{1}{g_T} \cdot \sqrt{\gamma \delta (1 - |c|^2)}$$

"Noise-Match"

* This is not the same as power match

$$Y_s = Y_{in}^*$$

$$F \uparrow \text{ as } \frac{1}{f_T} \uparrow$$

* For higher frequency operation $f \uparrow$
 \Rightarrow Need higher f_T

⇒ better to use "fasten" process.

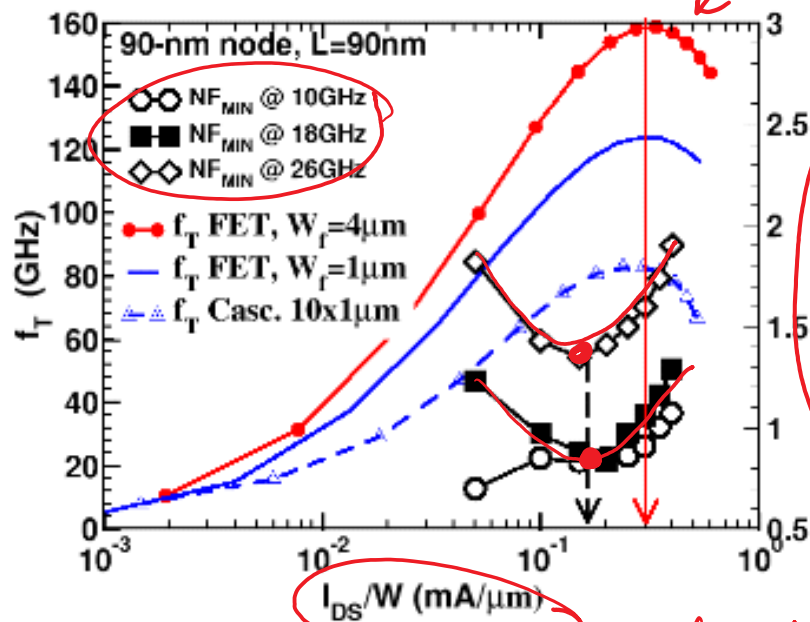
* We trade-off noise matching with power matching

∴ noise match \neq conjugate match

* In the book a generic model is given from

Eqn 4.142 - 4.147

Substitute $R_i = 0$ for CMOS technology.



Current Density $J_s = \frac{I_D}{W}$